Application/Control No. Applicant(s)/Patent Under Reexamination 10/663,714 **INOUE ET AL** Notice of References Cited Examiner Art Unit Page 1 of 1 A. Sefer 2826 **U.S. PATENT DOCUMENTS Document Number** Date Classification Name Country Code-Number-Kind Code MM-YYYY US-2003/0010993 01-2003 NAKAMURA et al. 257/99 Α В US-US-C US-D US-Ε US-F US-G US-Н US-US-US-K US-US-М FOREIGN PATENT DOCUMENTS **Document Number** Date Classification Country Name Country Code-Number-Kind Code MM-YYYY Ν 0 Р Q R S Т **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) U W

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